

STP5NK80Z STP5NK80ZFP

N-channel 800V - 1.9Ω - 4.3A - TO-220/TO-220FP Zener-protected SuperMESH[™] Power MOSFET

General features

| Туре | V _{DSS} (@Tjmax) | R _{DS(on)} | I _D |
|-------------|------------------------------|---------------------|----------------|
| STP5NK80Z | 800 V | < 2.4 Ω | 4.3 A |
| STP5NK80ZFP | 800 V | < 2.4 Ω | 4.3 A |

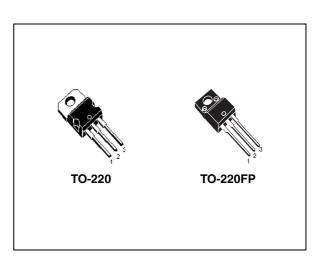
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatibility

Description

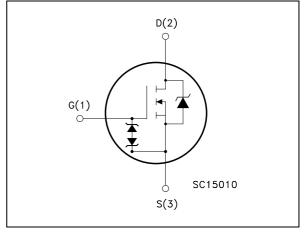
The SuperMESH[™] series is obtained through an extreme optimization of ST's well established strip-based PowerMESH[™] layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh[™] products.

Applications

Switching application



Internal schematic diagram



Order codes

| Part number | Marking | Package | Packaging |
|-------------|-----------|----------|-----------|
| STP5NK80Z | P5NK80Z | TO-220 | Tube |
| STP5NK80ZFP | P5NK80ZFP | TO-220FP | Tube |

| August | 2006 |
|--------|------|
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1 Electrical ratings

| Table I. | Absolute maximum ratings | | | |
|------------------------------------|--|--------|---------------------|------|
| Symbol | Parameter | Val | ue | Unit |
| | | TO-220 | TO-220FP | |
| V _{DS} | Drain-source voltage ($V_{GS} = 0$) | 80 | 00 | V |
| V _{GS} | Gate-source voltage | ± 3 | 30 | V |
| ۱ _D | Drain current (continuous) at $T_C = 25^{\circ}C$ | 4.3 | 4.3 ⁽¹⁾ | А |
| I _D | Drain current (continuous) at $T_C=100^{\circ}C$ | 2.7 | 2.7 ⁽¹⁾ | А |
| I _{DM} ⁽²⁾ | Drain current (pulsed) | 17.2 | 17.2 ⁽¹⁾ | А |
| P _{TOT} | Total dissipation at $T_{C} = 25^{\circ}C$ | 110 | 30 | W |
| | Derating factor | 0.88 | 0.24 | W/°C |
| V _{ESD(G-S)} | Gate source ESD (HBM-C=100pF, R=1.5KΩ) | 350 | 00 | V |
| dv/dt ⁽³⁾ | Peak diode recovery voltage slope | 4. | 5 | V/ns |
| V _{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1s; T_c = 25°C) | - | 2500 | v |
| T _J T _{stg} | Operating junction temperature Storage temperature | -55 tc | 0 150 | °C |

Table 1. Absolute maximum ratings

1. Limited only by maximum temperature allowed

2. Pulse width limited by safe operating area

3. $I_{SD} \leq 4.3A$, di/dt 200A/µs, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq T_{JMAX}$.

Table 2.Thermal data

| Symbol | Parameter | Value | | Unit |
|-----------------------|---|--------|----------|------|
| | | TO-220 | TO-220FP | |
| R _{thj-case} | Thermal resistance junction-case max | 1.14 | 4.2 | °C/W |
| R _{thj-a} | Thermal resistance junction-ambient max | 62 | .5 | °C/W |
| Τ _Ι | Maximum lead temperature for soldering purpose | 30 | 00 | °C |



| Symbol | Parameter | Value | Unit |
|-----------------|---|-------|------|
| I _{AR} | Avalanche current, repetitive or not-repetitive (pulse width limited by Tj Max) | 4.3 | A |
| E _{AS} | Single pulse avalanche energy (starting Tj=25°C, Id=Iar, Vdd=50V) | 190 | mJ |

Table 3. Avalanche characteristics

Table 4. Gate-source zener diode

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|-------------------|-------------------------------|------------------------|------|------|------|------|
| BV _{GSO} | Gate-source breakdown voltage | Igs=± 1mA (Open Drain) | 30 | | | V |

1.1 Protection features of gate-to-source zener diodes

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.



2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|----------------------|--|---|------|------|---------|----------|
| V _{(BR)DSS} | Drain-source breakdown voltage | $I_D = 1mA$, $V_{GS} = 0$ | 800 | | | V |
| I _{DSS} | Zero gate voltage drain current (V _{GS} = 0) | $V_{DS} = Max rating,$ $V_{DS} = Max rating,$ $Tc = 125^{\circ}C$ | | | 1 50 | μΑ μΑ |
| I _{GSS} | Gate body leakage current $(V_{GS} = 0)$ | $V_{GS} = \pm 20V$ | | | ±10 | μA |
| V _{GS(th)} | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 100 \mu A$ | 3 | 3.75 | 4.5 | V |
| R _{DS(on)} | Static drain-source on resistance | V _{GS} = 10V, I _D = 2.15 A | | 1.9 | 2.4 | Ω |

Table 5. On/off states

Table 6. Dynamic

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|---|--|--|------|----------------------|------|----------------------|
| g _{fs} ⁽¹⁾ | Forward transconductance | V _{DS} =15V, I _D = 2.15A | | 4.25 | | S |
| C _{iss} C _{oss} C _{rss} | Input capacitance Output capacitance Reverse transfer capacitance | V _{DS} =25V, f=1 MHz, V _{GS} =0 | | 910 98 20 | | pF pF pF |
| C _{osseq} ⁽²⁾ | Equivalent output capacitance | V_{GS} =0, V_{DS} =0V to 400V | | 40 | | pF |
| t _{d(on)} t _r t _{d(off)} t _r | Turn-on delay time Rise time Turn-on delay time fall time | V_{DD} =400 V, I_D = 2 A, R_G =4.7 Ω , V_{GS} =10V (see <i>Figure 18</i>) | | 18 25 45 30 | | ns ns ns ns |
| Q _g Q _{gs} Q _{gd} | Total gate charge Gate-source charge Gate-drain charge | V _{DD} =640V, I _D = 4.3A V _{GS} =10V | | 32.4 5 18.5 | 45.5 | nC nC nC |
| t _{d(Voff)} t _r | Off-voltage rise time Fall time Cross-over time | V_{DD} =640 V, I _D = 4.3 A, R _G =4.7 Ω , V _{GS} =10V (see <i>Figure 20</i>) | | 22 10 32 | | ns ns ns |

1. Pulsed: pulse duration=300µs, duty cycle 1.5%

2. $C_{oss\ eq}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



| Symbol | Parameter | Test conditions | Min | Тур. | Max | Unit |
|--|--|--|-----|----------------|------|---------------|
| I _{SD} | Source-drain current | | | | 4.3 | А |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | | | 17.2 | А |
| V _{SD} ⁽²⁾ | Forward on voltage | I _{SD} = 4.3 A, V _{GS} =0 | | | 1.6 | V |
| t _{rr} Q _{rr} I _{RRM} | Reverse recovery time Reverse recovery charge Reverse recovery current | I _{SD} = 4.3 A, di/dt = 100A/μs, V _{DD} =40 V, Tj = 150°C (see <i>Figure 20</i>) | | 500 3 12 | | ns μC Α |

Table 7.Source drain diode

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration=300µs, duty cycle 1.5%



2.1 Electrical characteristics (curves)

Figure 1. Safe operating area for TO-220

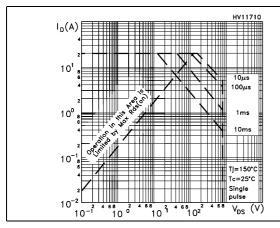
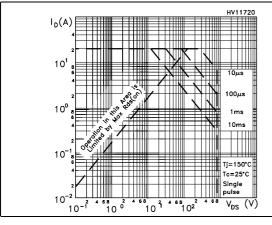
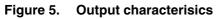
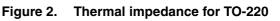


Figure 3. Safe operating area for TO-220FP (HV11720)





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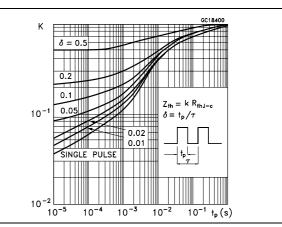


Figure 4. Thermal impedance for TO-220FP

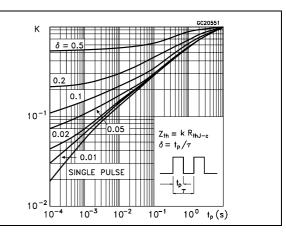


Figure 6. Transfer characteristics

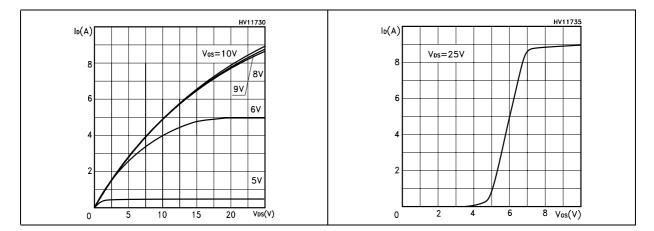
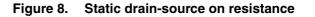


Figure 7. Transconductance



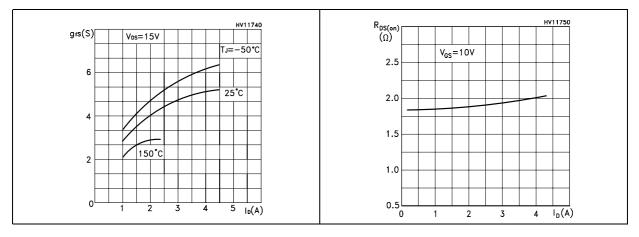
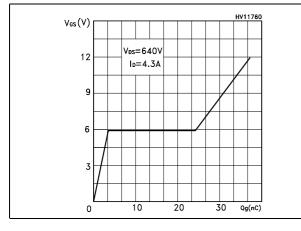


Figure 9. Gate charge vs gate-source voltage Figure 10. Capacitance variations



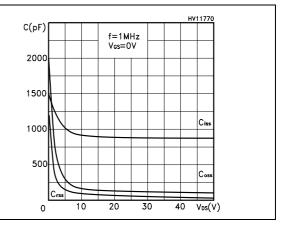


Figure 11. Normalized gate threshold voltage vs temperature

Figure 12. Normalized on resistance vs temperature

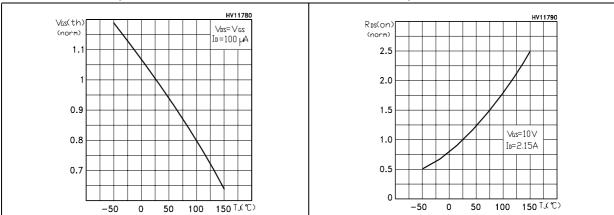




Figure 13. Source-drain diode forward characteristics

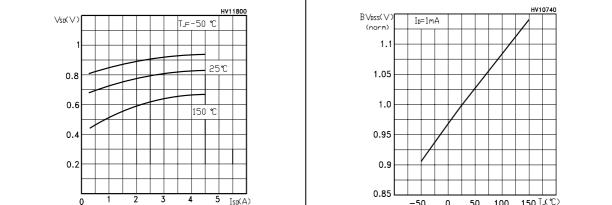


Figure 15. Avalanche energy vs temperature

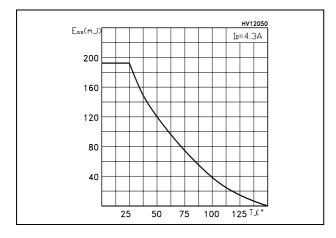
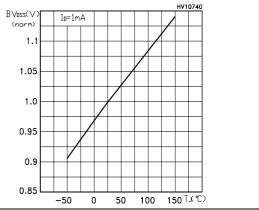


Figure 14. Normalized BVdss vs temperature



3 Test circuit

Figure 16. Unclamped Inductive load test circuit

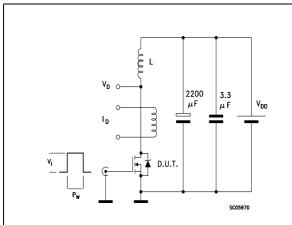
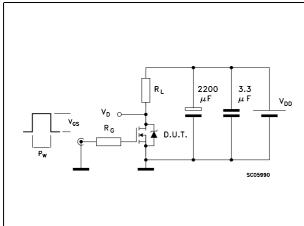
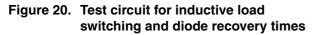


Figure 18. Switching times test circuit for resistive load





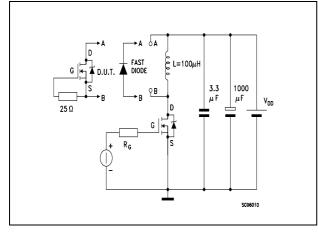
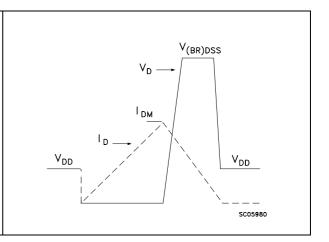
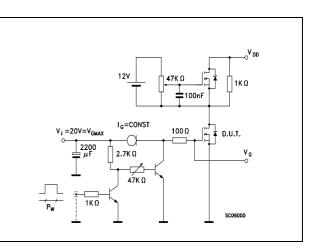


Figure 17. Unclamped Inductive waveform









4 Package mechanical data

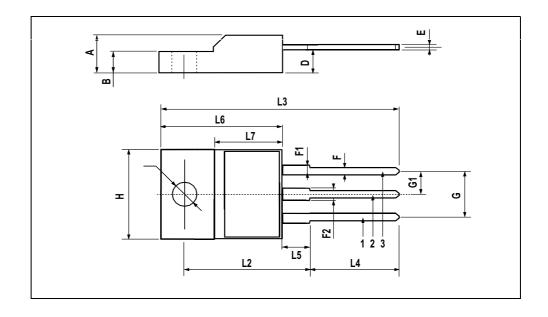
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



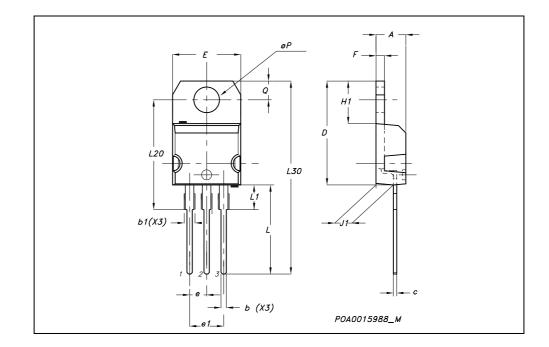
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| DIM. | | mm. | | | inch | | |
|------|------|-----|------|-------|-------|-------|--|
| DIM. | MIN. | ТҮР | MAX. | MIN. | TYP. | | |
| А | 4.4 | | 4.6 | 0.173 | | 0.181 | |
| В | 2.5 | | 2.7 | 0.098 | | 0.106 | |
| D | 2.5 | | 2.75 | 0.098 | | 0.108 | |
| Е | 0.45 | | 0.7 | 0.017 | | 0.027 | |
| F | 0.75 | | 1 | 0.030 | | 0.039 | |
| F1 | 1.15 | | 1.7 | 0.045 | | 0.067 | |
| F2 | 1.15 | | 1.7 | 0.045 | | 0.067 | |
| G | 4.95 | | 5.2 | 0.195 | | 0.204 | |
| G1 | 2.4 | | 2.7 | 0.094 | | 0.106 | |
| Н | 10 | | 10.4 | 0.393 | | 0.409 | |
| L2 | | 16 | | | 0.630 | | |
| L3 | 28.6 | | 30.6 | 1.126 | | 1.204 | |
| L4 | 9.8 | | 10.6 | .0385 | | 0.417 | |
| L5 | 2.9 | | 3.6 | 0.114 | | 0.141 | |
| L6 | 15.9 | | 16.4 | 0.626 | | 0.645 | |
| L7 | 9 | | 9.3 | 0.354 | | 0.366 | |
| Ø | 3 | | 3.2 | 0.118 | | 0.126 | |





| TO-220 MECHANICAL DATA | | | | | | | |
|------------------------|-------|-------|-------|-------|-------|-------|--|
| DIM. | mm. | | | inch | | | |
| | MIN. | TYP | MAX. | MIN. | TYP. | MAX. | |
| Α | 4.40 | | 4.60 | 0.173 | | 0.181 | |
| b | 0.61 | | 0.88 | 0.024 | | 0.034 | |
| b1 | 1.15 | | 1.70 | 0.045 | | 0.066 | |
| С | 0.49 | | 0.70 | 0.019 | | 0.027 | |
| D | 15.25 | | 15.75 | 0.60 | | 0.620 | |
| E | 10 | | 10.40 | 0.393 | | 0.409 | |
| е | 2.40 | | 2.70 | 0.094 | | 0.106 | |
| e1 | 4.95 | | 5.15 | 0.194 | | 0.202 | |
| F | 1.23 | | 1.32 | 0.048 | | 0.052 | |
| H1 | 6.20 | | 6.60 | 0.244 | | 0.256 | |
| J1 | 2.40 | | 2.72 | 0.094 | | 0.107 | |
| L | 13 | | 14 | 0.511 | | 0.551 | |
| L1 | 3.50 | | 3.93 | 0.137 | | 0.154 | |
| L20 | | 16.40 | | | 0.645 | | |
| L30 | | 28.90 | | | 1.137 | | |
| øP | 3.75 | | 3.85 | 0.147 | | 0.151 | |
| Q | 2.65 | | 2.95 | 0.104 | | 0.116 | |



5 Revision history

Table 8. Revision history

| Date | Revision | Changes |
|-------------|----------|---------------------------------|
| 09-Sep-2004 | 2 | Preliminary version |
| 06-Sep-2005 | 3 | Final version |
| 16-Aug-2006 | 4 | New template, no content change |



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